Notice of References Cited Application/Control No. 10/622,144 Examiner DAVID P. RASHID Applicant(s)/Patent Under Reexamination WIEDEMANN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,640,468	06-1997	Hsu, Shin-yi	382/190
*	В	US-6,618,490	09-2003	Cham et al.	382/103
	U	US-			
	ם	US-			
	ш	US-			
	F	US-			
	O	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U	Statistical Framework for Long-Range Feature Matching in Uncalibrated Image Mosaicing, Cham et al., Computer Vision and Pattern Recognition, 1998 pp. 1-6		
	\ \			
	w			
	x			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.